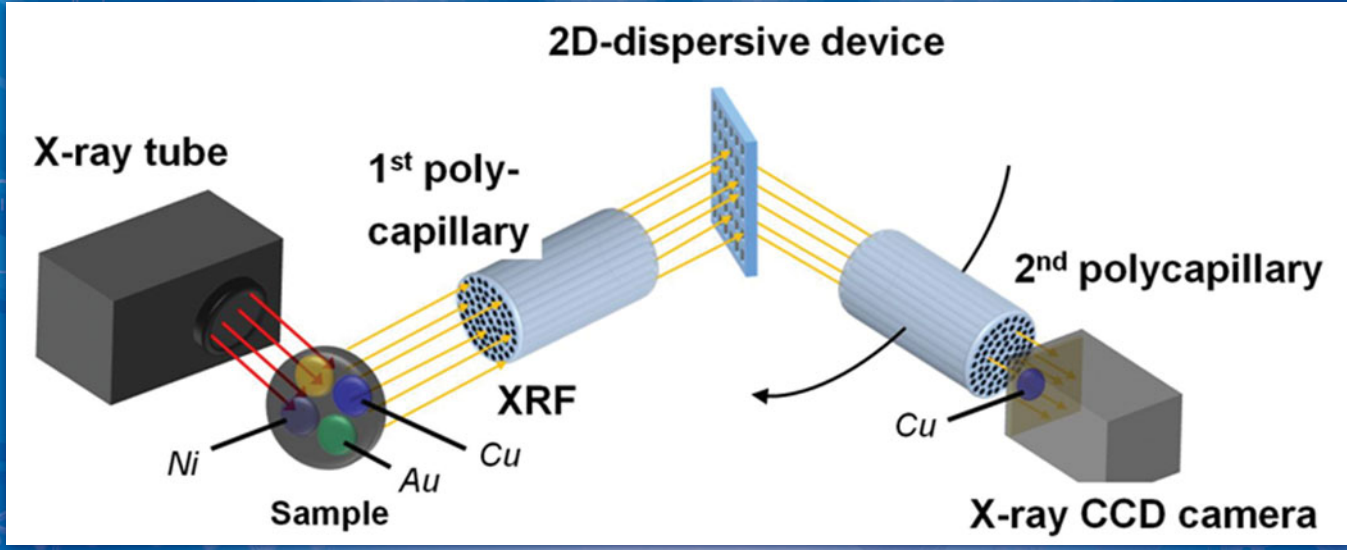
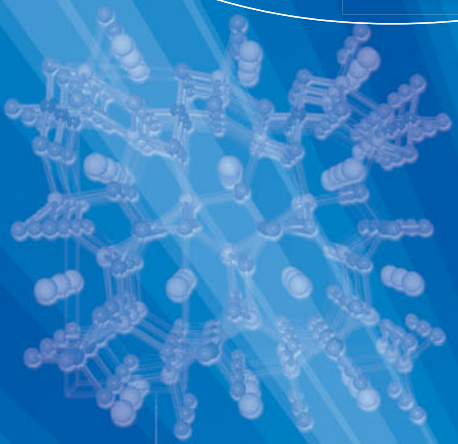


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EDITORIALS

Ting C. Huang	Special issue on representative articles from 2011 Denver X-ray Conference	69
Tom Blanton and George Havrilla	Sixtieth Denver X-ray Conference and selected papers for the special June <i>Powder Diffraction</i> issue	70

TECHNICAL ARTICLES

Takashi Ohmori, Masatoshi Hatayama, Tadayuki Ohchi, Hisashi Ito, Hisataka Takenaka, and Kouichi Tsuji	Development of X-ray 2D dispersive device for WD-XRF imaging spectrometer	71
Martina Schmeling, Donald S. Burnett, Amy J. G. Jurewicz, and Igor V. Veryovkin	Steps toward accurate large-area analyses of Genesis solar wind samples: evaluation of surface cleaning methods using total reflection X-ray fluorescence spectrometry	75
Michael J. Haugh, Michael R. Charest, Patrick W. Ross, Joshua J. Lee, Marilyn B. Schneider, Nathan E. Palmer, and Alan T. Teruya	Calibration of X-ray imaging devices for accurate intensity measurement	79
F. J. Cadieu, I. Vander, Y. Rong, and R. W. Zuneska	X-ray measurements of nanometer-thick tantalum oxide and hafnium oxide films on silicon substrates for thickness and composition determination	87
Conal E. Murray, E. Todd Ryan, Paul R. Besser, Christian Witt, Jean L. Jordan-Sweet, and Michael F. Toney	Understanding stress gradients in microelectronic metallization	92
Peter W. Stephens, James A. Kaduk, Thomas N. Blanton, David R. Whitcomb, Scott T. Misture, and Manju Rajeswaran	Structure determination of the silver carboxylate dimer $[\text{Ag}(\text{O}_2\text{C}_{20}\text{H}_{39})]_2$, silver arachidate, using powder X-ray diffraction methods	99
Thomas N. Blanton, and Debasis Majumdar	X-ray diffraction characterization of polymer intercalated graphite oxide	104
Mark A. Rodriguez, Paul G. Kotula, James J. M. Griego, Jason E. Heath, Stephen J. Bauer, and Daniel E. Wesolowski	Multivariate statistical analysis of micro-X-ray fluorescence spectral images	108
Thomas Gnäupel-Herold	A software for diffraction stress factor calculations for textured materials	114
Eric N. Coker, Mark A. Rodriguez, Andrea Ambrosini, James E. Miller, and Ellen B. Stechel	Using <i>in-situ</i> techniques to probe high-temperature reactions: thermochemical cycles for the production of synthetic fuels from CO_2 and water	117
Shouwen Shen, Syed R. Zaidi, Bader A. Mutairi, Ahmed A. Shehry, Husin Sitepu, Saud A. Hamoud, Fahad S. Khaldi, and Fatimah A. Edhaim	Quantitative XRD bulk and clay mineralogical determination of paleosol sections of Unayzah and Basal Khuff clastics in Saudi Arabia	126

J. L. Garin, and R. L. Mannheim	Rietveld quantitative analysis of cast super duplex steel	131
Roy G. Baggerly	Electrolytic phase extraction: a useful technique to evaluate precipitates in nitinol	136

INTERNATIONAL REPORT

Tess Kozul	2012 ICDD Annual Spring Meetings	140
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CALENDAR

Calendar of Forthcoming Meetings <i>Powder Diffraction June 2012</i>	147
Calendar of Short Courses and Workshops <i>Powder Diffraction June 2012</i>	148
Denver X-ray Conference Program	149
Cumulative Author Index	169

Powder Diffraction

An International Journal of Materials Characterization

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On the cover: WDXRF spectrometer equipped with 2D dispersive device, polycapillary optics and x-ray CCD camera. (Courtesy of Takashi Ohmori, Masatoshi Hatayama, Tadayuki Ohchi, Hisashi Ito, Hisataka Takenaka, and Kouichi Tsuji).

Powder Diffraction is a quarterly journal published by the JCPDS-International Centre for Diffraction Data through Cambridge University Press.

Powder Diffraction is a journal of practical technique, publishing articles relating to the widest range of application—from materials analysis to epitaxial growth of thin films and to the latest advances in software. Although practice will be emphasized, theory will not be neglected, especially as its discussion will relate to better understanding of technique.

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Subscription rates to Eastern Hemisphere include air freight service.

Back-Number Prices. 2012 single copies: \$62.

Subscription, renewals, and address changes should be addressed to Subscription Fulfillment, *Powder Diffraction*, Cambridge University Press, 100 Brook Hill Drive, West Nyack, NY 10013-2113 (for U.S.A., Canada, and Mexico); or Cambridge University Press, The Edinburgh Building, Shaftsbury Road, Cambridge, CB2 8RU, Cambridge, England (for UK and elsewhere). Allow at least six weeks advance notice. For address changes please send both old and new addresses and, if possible, include a mailing label from the wrapper of a recent issue.

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Powder Diffraction (ISSN: 0885-7156) is published quarterly (4X annually) by the JCPDS-International Centre for Diffraction Data through Cambridge University Press, 32 Avenue of the Americas, New York, NY 10013-2473. POSTMASTER: Send address changes to *Powder Diffraction*, Cambridge University Press, 100 Brook Hill Drive West Nyack, NY 10994-2113, USA. Periodicals postage paid in New York, NY and additional mailing offices.

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